

Evaluation of rotating electrode Electrical Discharge Machining (EDM) on molybdenum

In view of producing RF cavities

Plan.

- Intro.
- Technique EDM with rotating electrode.
- Results
 - Surface morphology.
 - Surface analysis.
 - Metrology.
- Concerns.
- Possible ways for improvement.

- Collaboration with the *Laboratoire NMP of Ecole d'Ingénieurs de Genève (EIG)*. R. Demellayer.
- First step, feasibility study: machining of 3 cavities on a pure Mo block by EDM with a rotating Copper electrode.



EDM

- Types of EDM:
 - Wire, die-sink, milling, rotating electrode.
- Parameters
 - Pulse on-time, off-time, current, open circuit voltage, work piece polarity, dielectric medium, electrode material, electrode speed...
- Well known procedures for conventional and less conventional materials, but **poor knowledge** for Mo as workpiece.
- Typical EDMS surface:
 - Topography: Cratered surface. Crater size and roughness depend on spark energy.
 - Metallurgical and Chemical effects on the affected layer (in conventional materials and methods < 0.13 mm for roughing settings, < 0.01 mm for finishing settings)
 - **Recast layer**. Experiences a rapid quench, in tension, solidification micro-cracks
 - **Heat affected zone**. Also in tension
- **Surface crack prediction maps:**

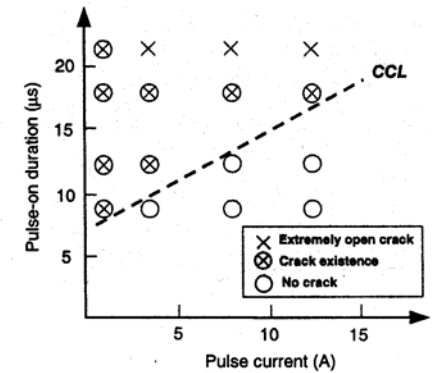
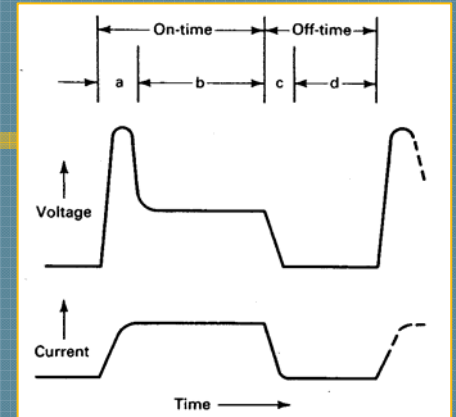


Fig. 10. The type of crack and the location of critical crack line (CCL) under different EDM conditions.

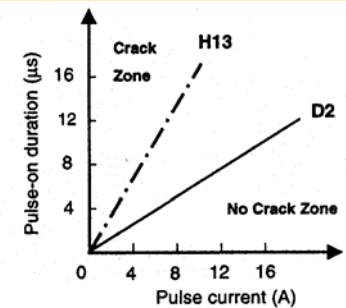
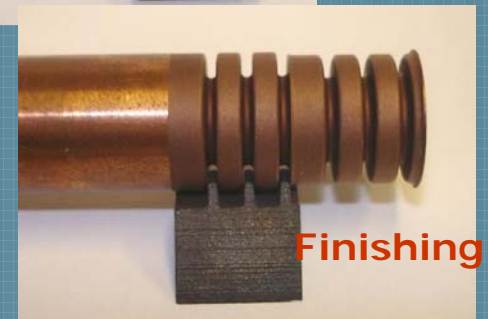
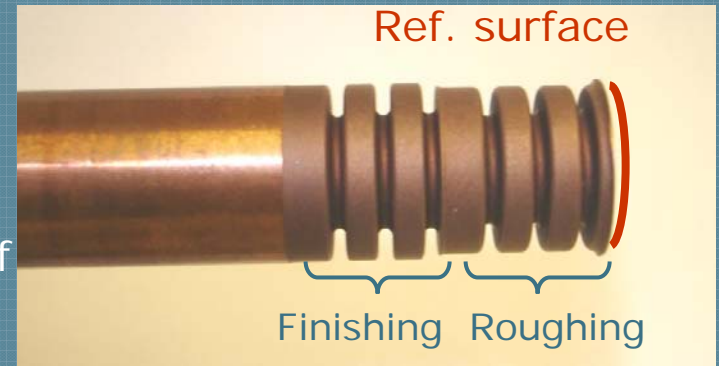


Fig. 12. Modified crack prediction map of tool steel D2 and H13. [36] Material: D2 and H13 tool steel, electrode: Copper.

Lee et al. 2004

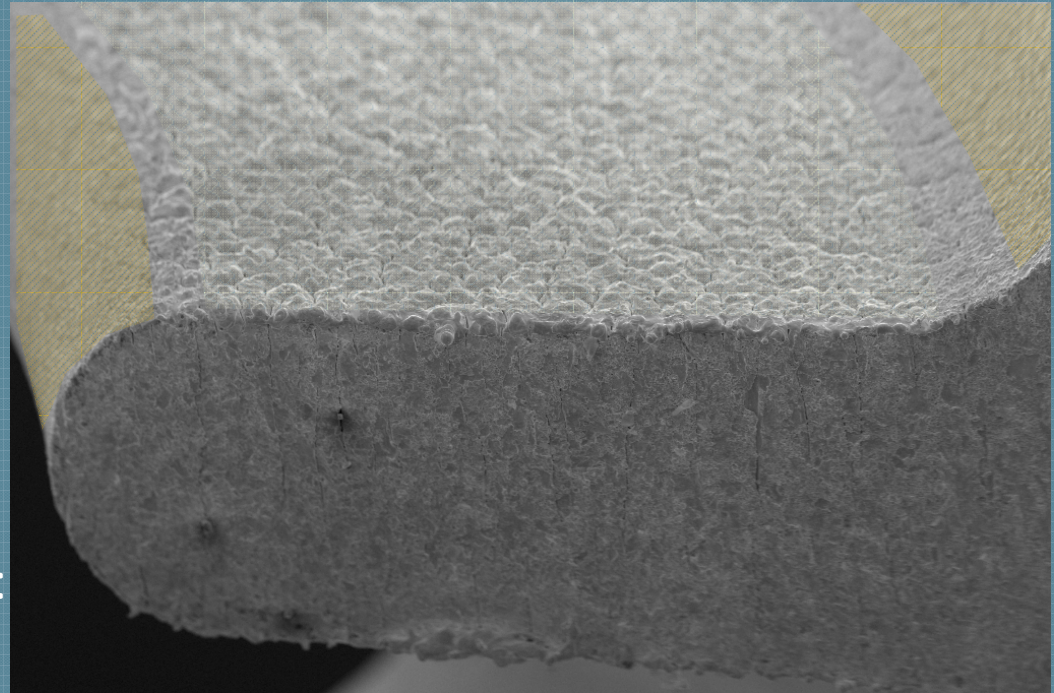
Technique EDM with rotating electrode.

- Fabrication of a high precision electrode.
 - From a copper bar.
 - By conventional wire EDM in water, the work piece is rotating.
 - Two regions within the same electrode: for roughing and for finishing.
 - Positioning reference surface: flat end of the electrode.
 - One Cu electrode per Mo piece.
 - Machining time: 24 h.
- Fabrication of the piece.
 - From a pure molybdenum bar.
 - By special EDM process with a **rotating electrode**, in oil.
 - Roughing and finishing runs.
 - One Cu electrode is consumed by piece. Erosion of the Cu is 20% that of the Mo piece.
 - Machining time: 24 h.



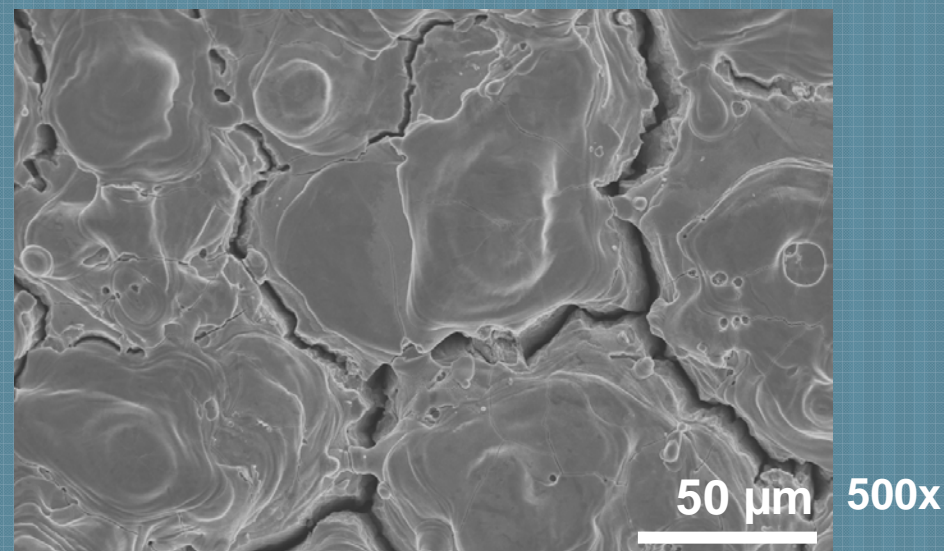
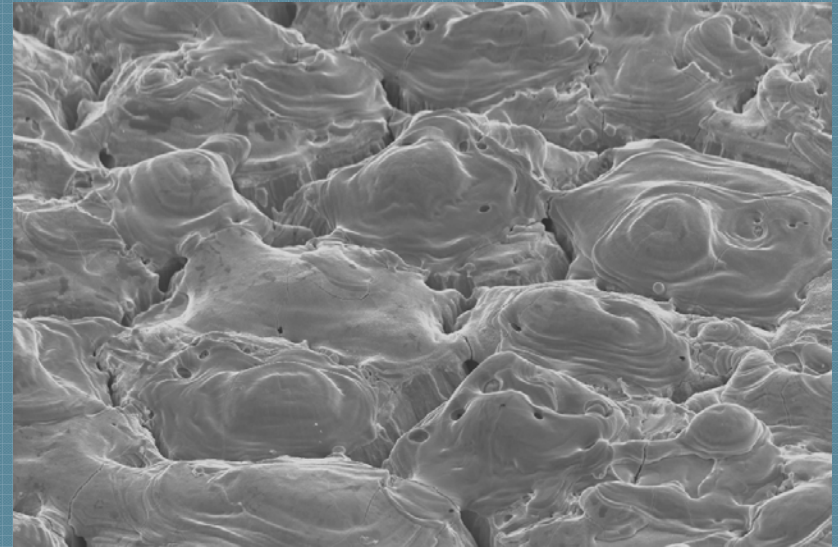
Results: Surface Morphology.

- Network of cracks.
- Two different regions:
 - Iris sides
 - Surface normal to the axis.
 - Surface that last longer exposed to the electrode.
 - Iris tips and cylindrical part of the cavity
 - Surface parallel to the axis.
 - Surface freshly exposed to the electrode.

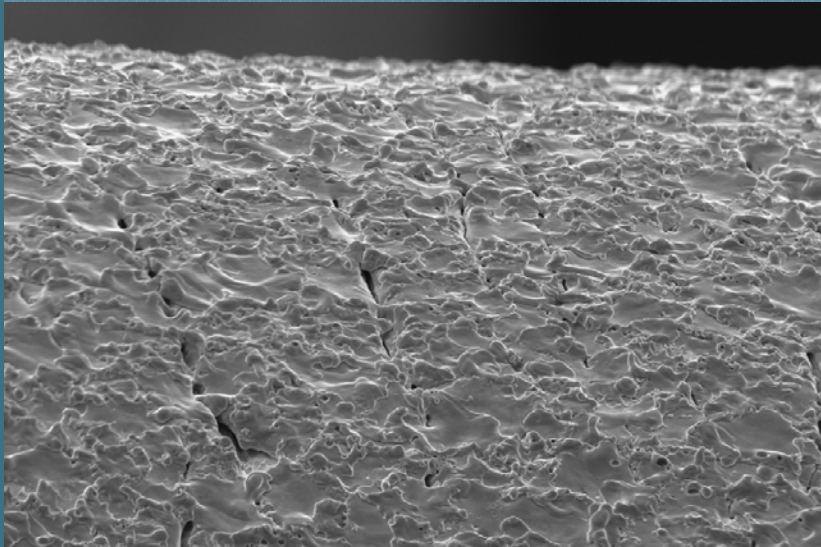


Results: Surface Morphology.

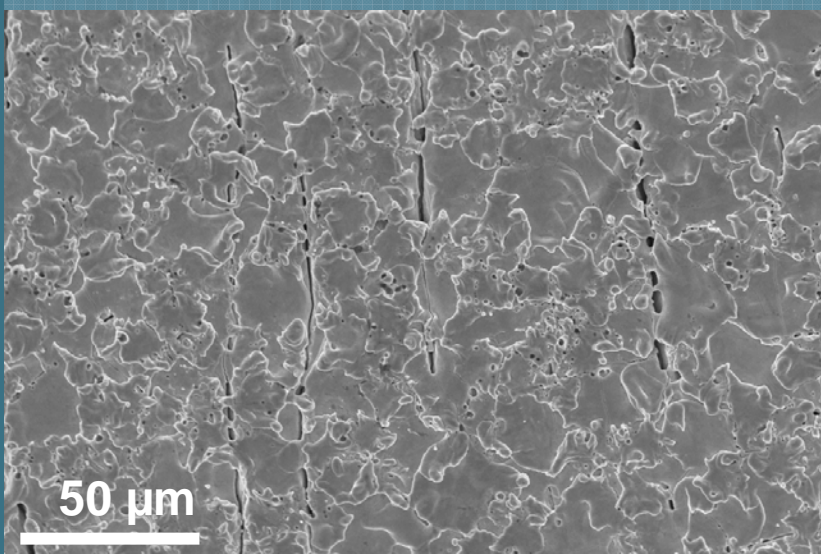
- Iris sides:
 - Network of cracks, mesh size 50-100 μm . (grain size 1-5 μm ; original powder particle size 2-10 μm)
 - Severe cracks.
 - "Ice cream-like" features on top of islands.
 - Rougher morphology than any other machined surface seen so far.



Results: Surface Morphology.



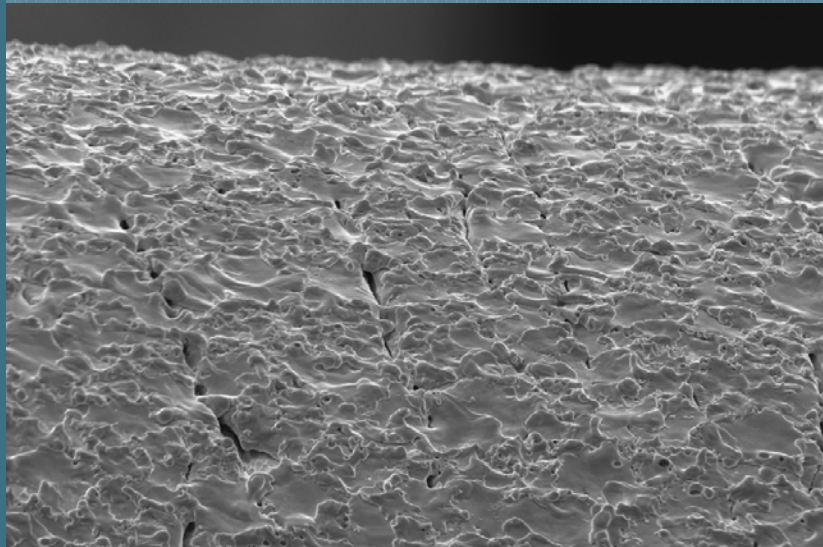
- Iris tip:
 - Cracks are straight and parallel to structure axis.
 - Less severe cracks
 - Typical EDM crater morphology.



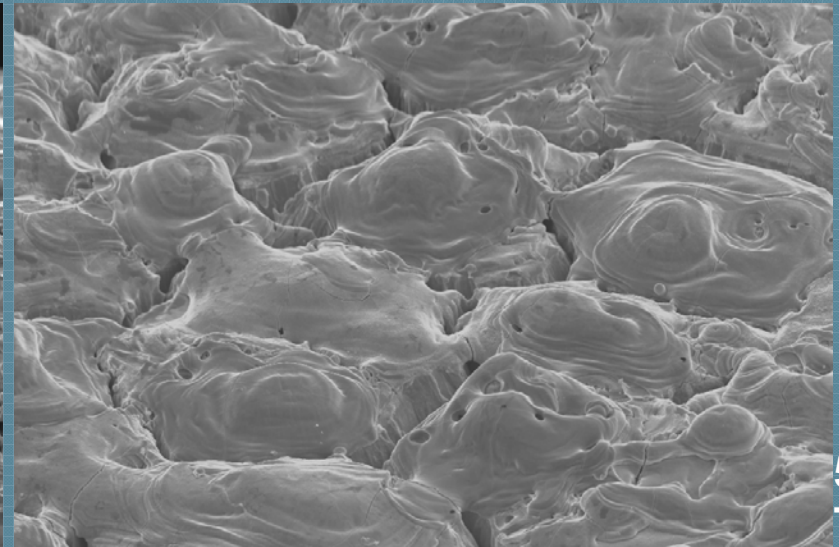
500x

50 μm

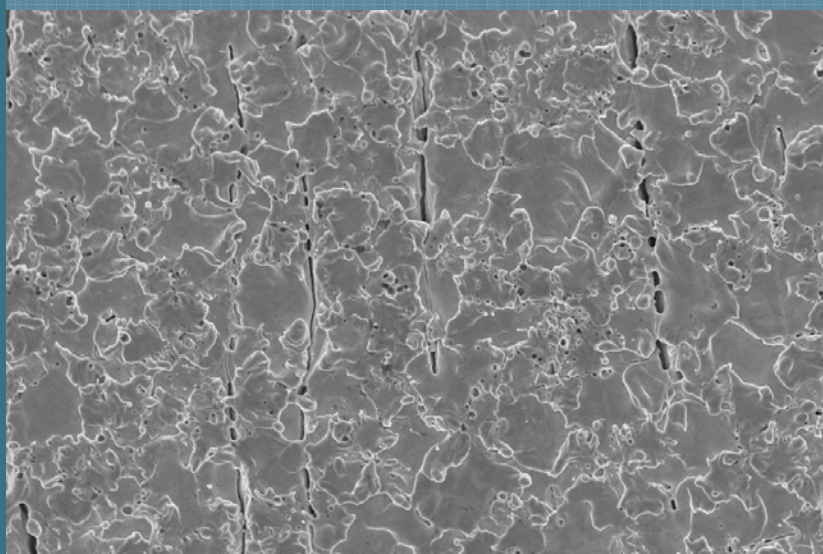
Results: Surface Morphology.



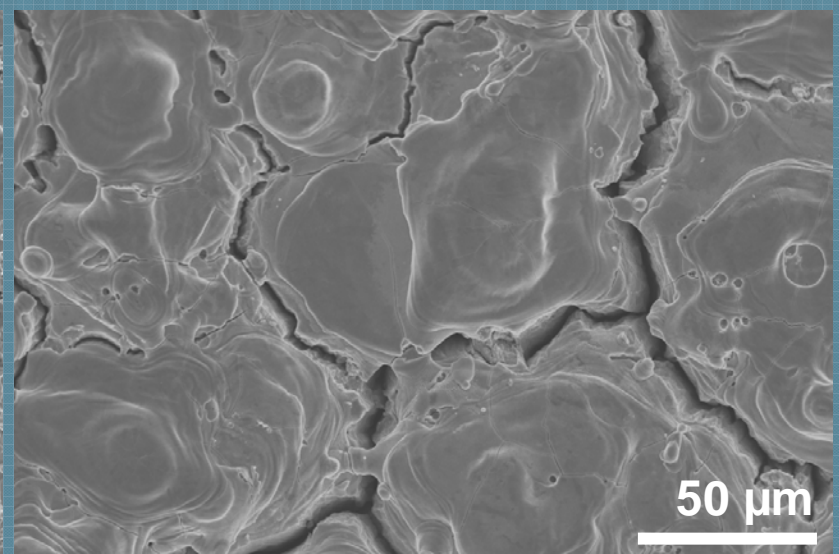
500x
Tilt 60°



500x
Tilt 60°



500x

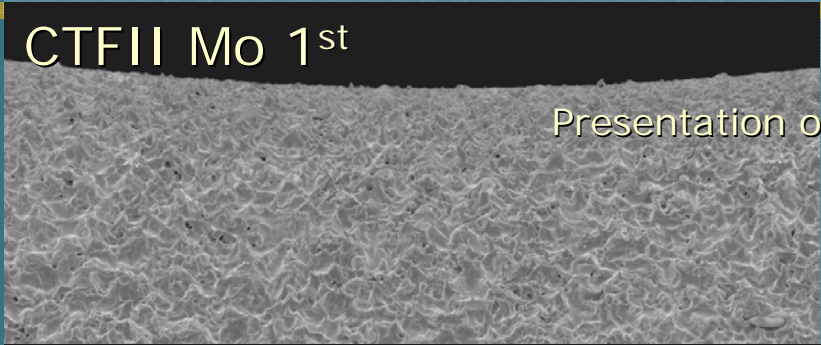


50 μ m

500x

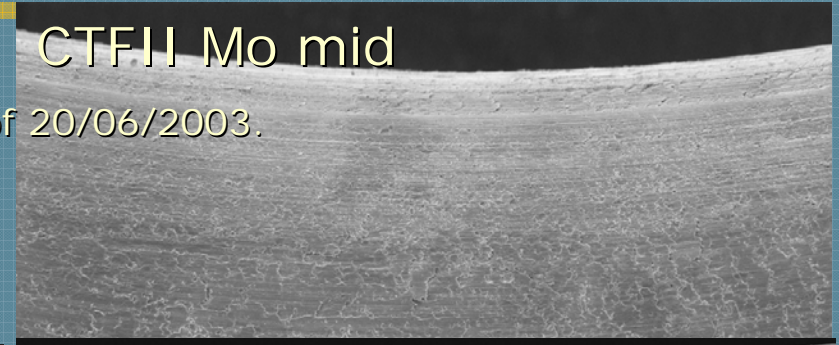
Comparison of iris tip surface morphology with historical records.

CTFII Mo 1st

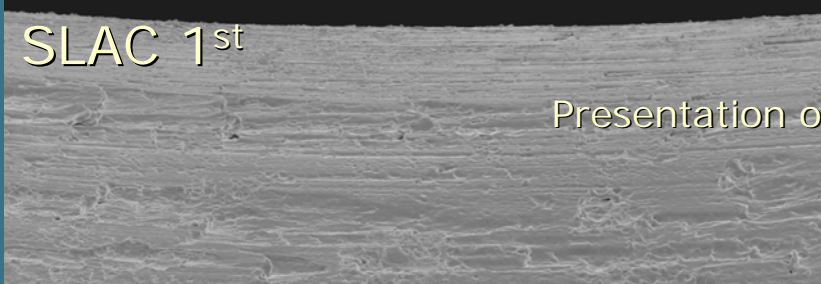


Presentation of 20/06/2003.

CTFII Mo mid

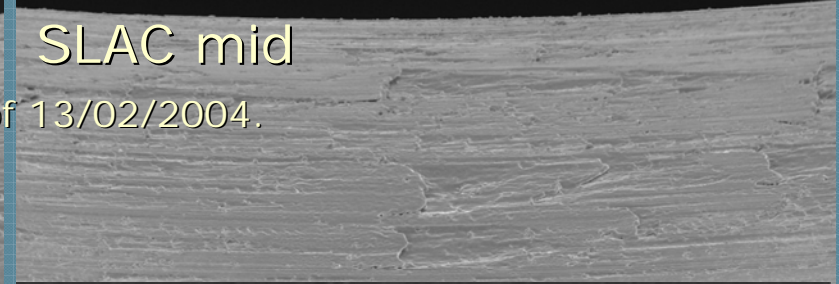


SLAC 1st

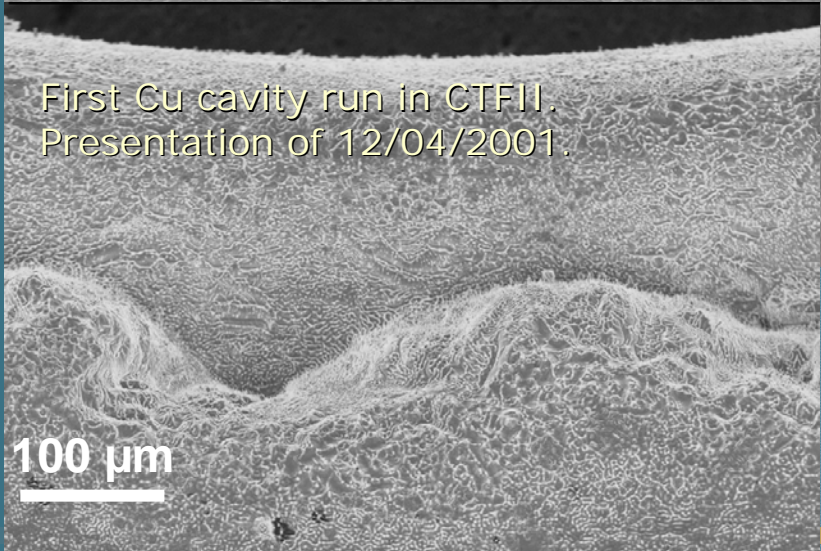


Presentation of 13/02/2004.

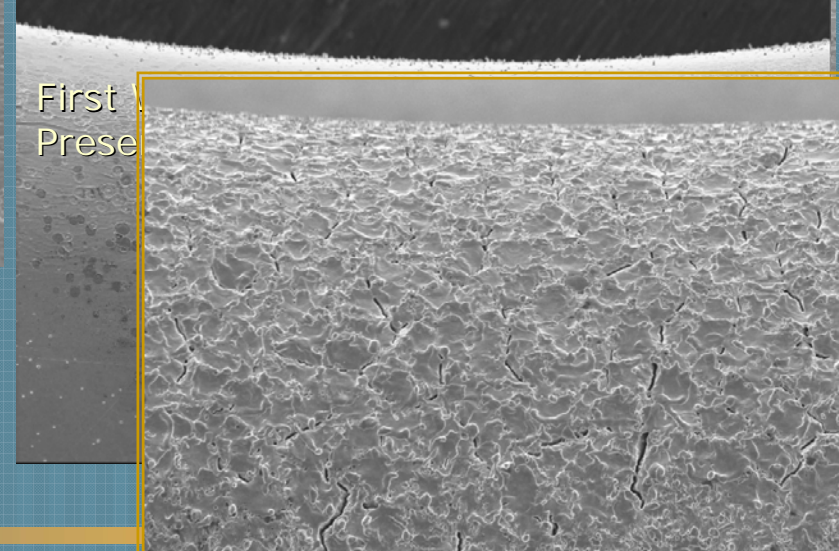
SLAC mid



First Cu cavity run in CTFII.
Presentation of 12/04/2001.



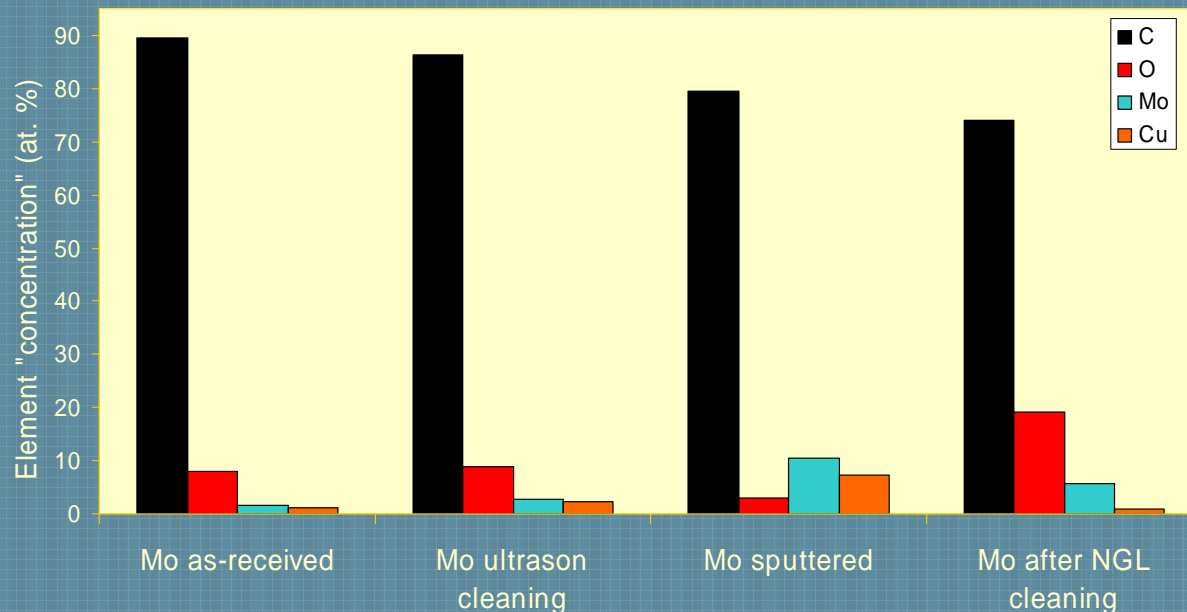
First
Prese



200x 100 μm

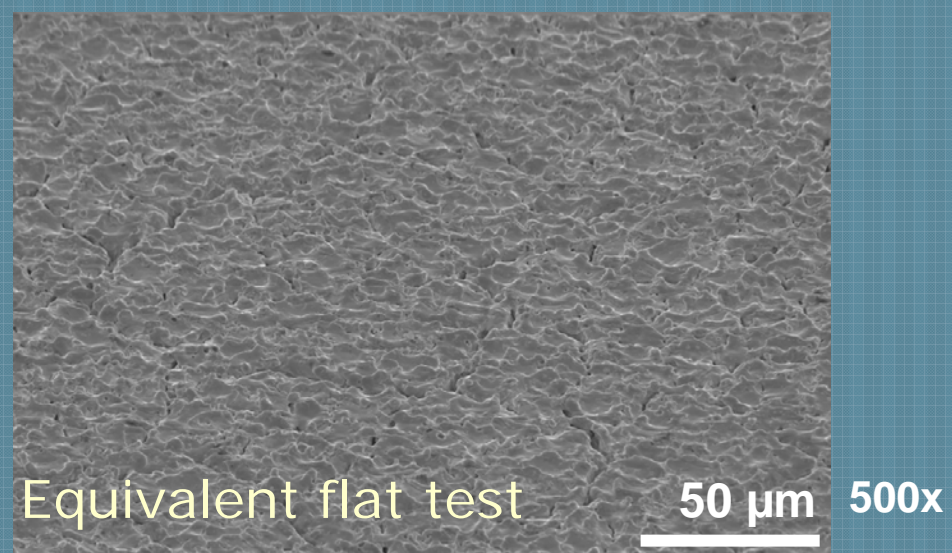
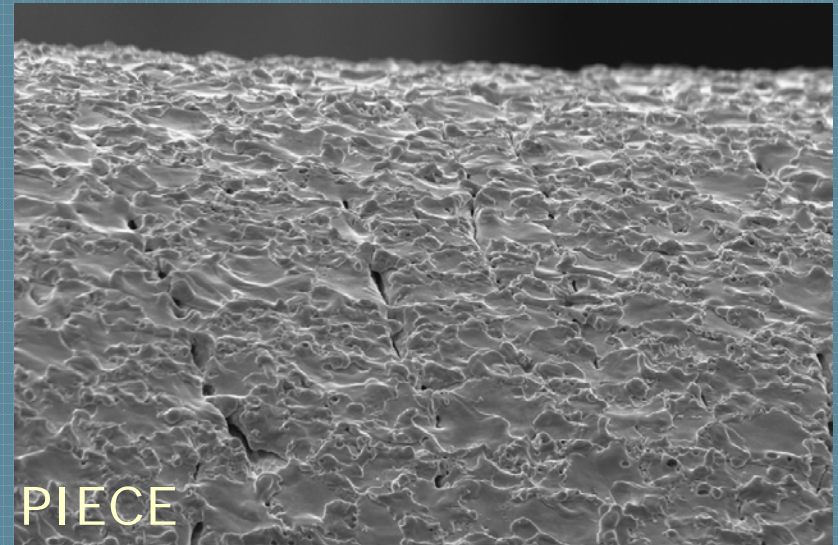
Results: Surface Analysis. (J. Gavillet TS/MME)

- XPS analyses as received and after cleaning steps. (Original aspect was bright, became dark after NGL cleaning)
- Thick carbonaceous layer not removed by standard cleaning methods.
- No carbide layer (Mo_2C or MoC)
- Some Cu transfer from electrode.



Results: Metrology.

- Roughness in equivalent flat test surface. At EIG $R_a=0.4 \mu\text{m}$.
- Roughness and dimensions at CERN: Pending.
- Optimizing dimensional tolerances was not a target at that stage. Electrode machining can be further optimized and number of finishing runs increased.



Concerns.

- Cracks and craters.
 - Mechanical weakness.
 - Electric field concentrators.
 - Retention of contamination: virtual leaks for UHV.
- Carbon contamination.
 - Degassing under service discharges.
- Dimensions.
- Mo versus Hybrid bimetallic.

Possible ways for improvement.

- These are first results produced. Far from optimized conditions.
- Use different pulse generator for more respect of the surface integrity (Charmilles development to cope with similar problems in EDM of WC-Co materials)
- Use different dielectric.
- Use Mo electrode.
- Add a 3rd finishing run (3rd region in the electrode).
- Optimize machining of electrode.
- End by an in situ electro-polishing (replace dielectric by electrolyte and use electrode as static electro-polishing electrode)
- Explore post treatments (better adapted cleanings, laser re-melting, acid etching, reverse sputtering,...)

- Possibility of institutional founding for joint projects: CTI-EIG-CERN-Charmilles.



Mag = 50 X
EHT = 20.00 kV
Detector = SE1

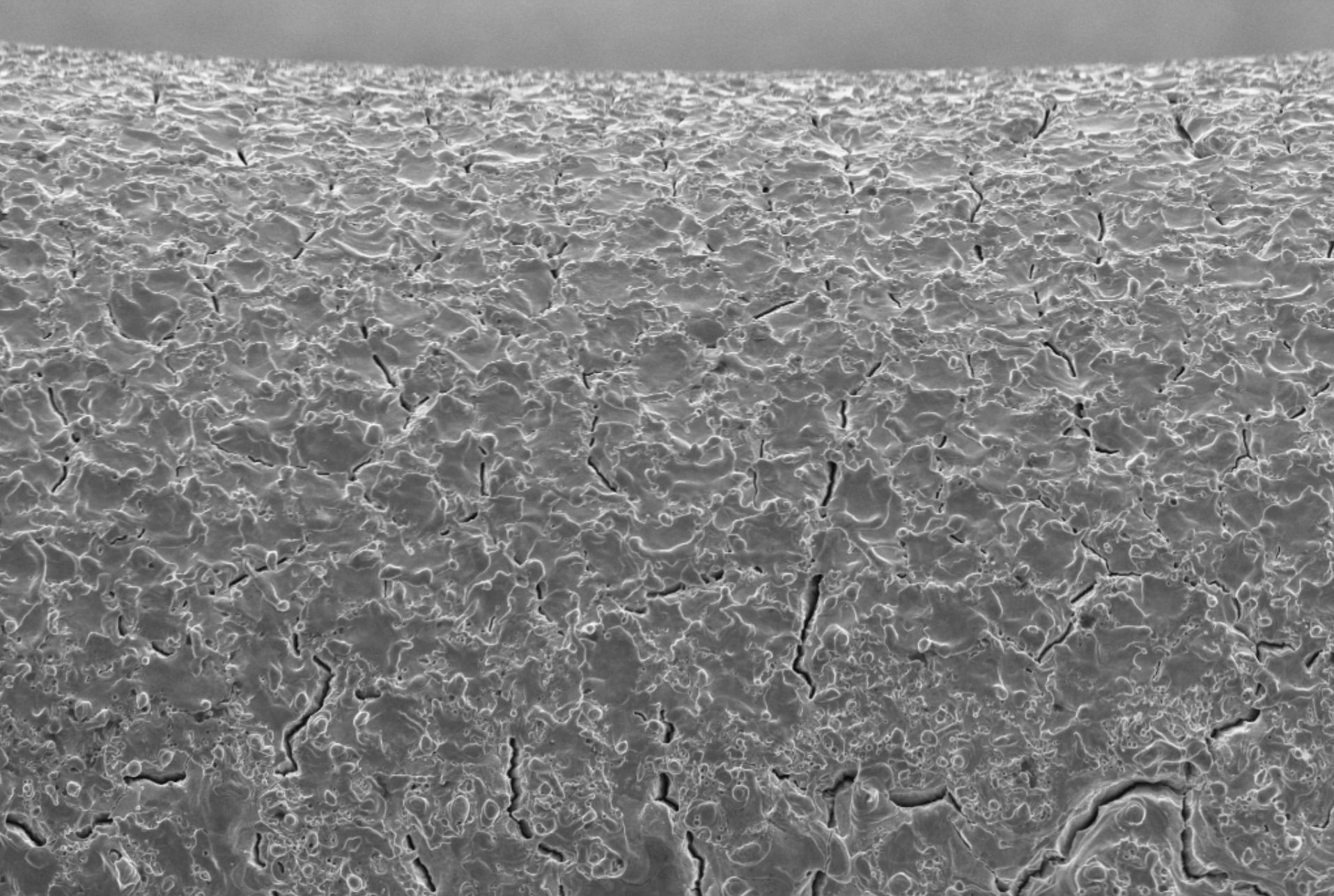
1mm

Mo. EDM sector at EIG-1. Axial section, Tilt=60.

File Name = EIG40.tif

Date :18 Oct 2004

G. Arnau TS/MME

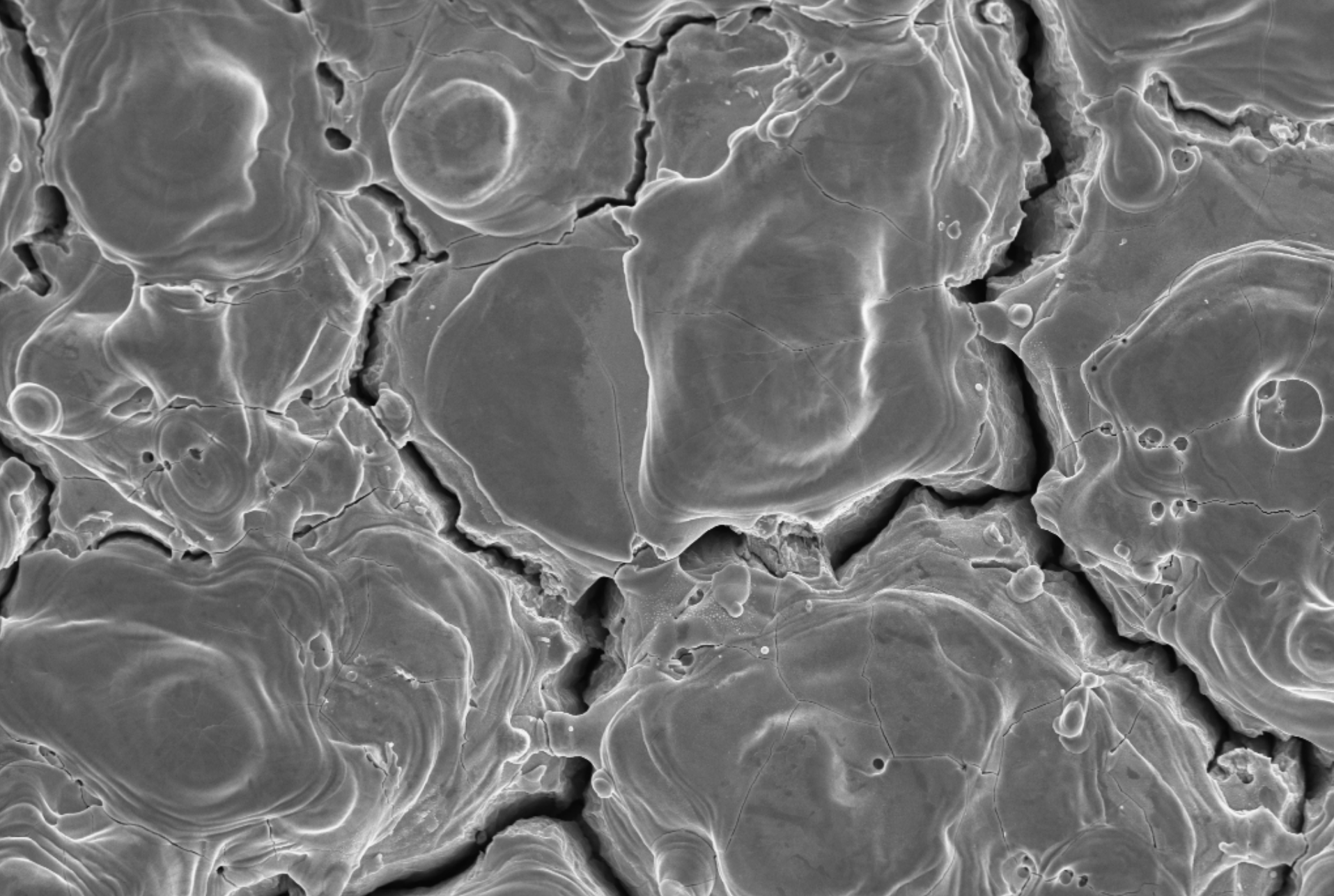


Mag = 200 X
EHT = 20.00 kV
Detector = SE1

100µm

Mo. EDM sector at EIG-1. Iris flat side.

File Name = EIG20.tif
Date :18 Oct 2004
G. Arnau TS/MME

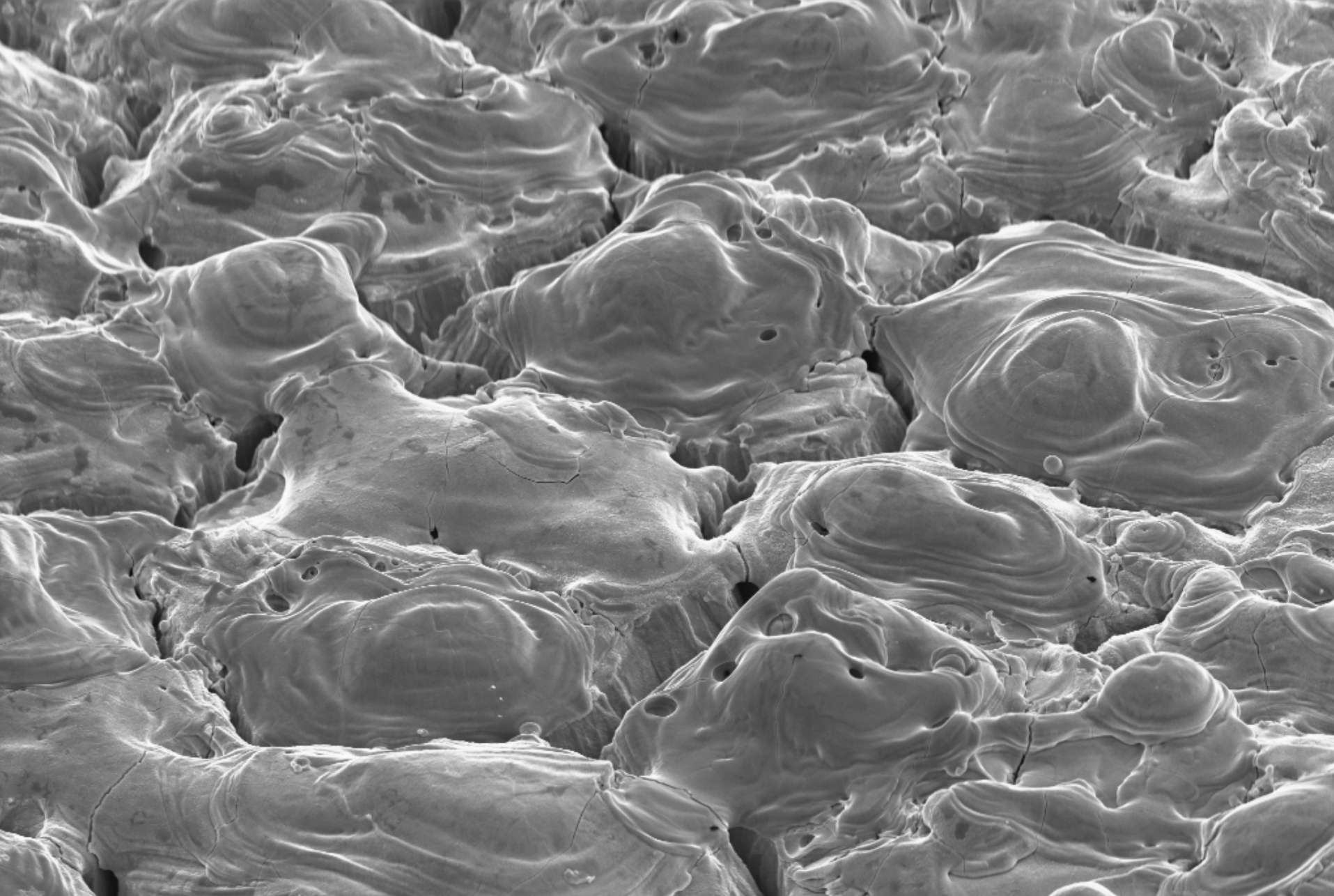


Mag = 500 X
EHT = 20.00 kV
Detector = SE1

100µm

Mo. EDM sector at EIG-1. Iris flat side.

File Name = EIG17.tif
Date :17 Oct 2004
G. Arnau TS/MME

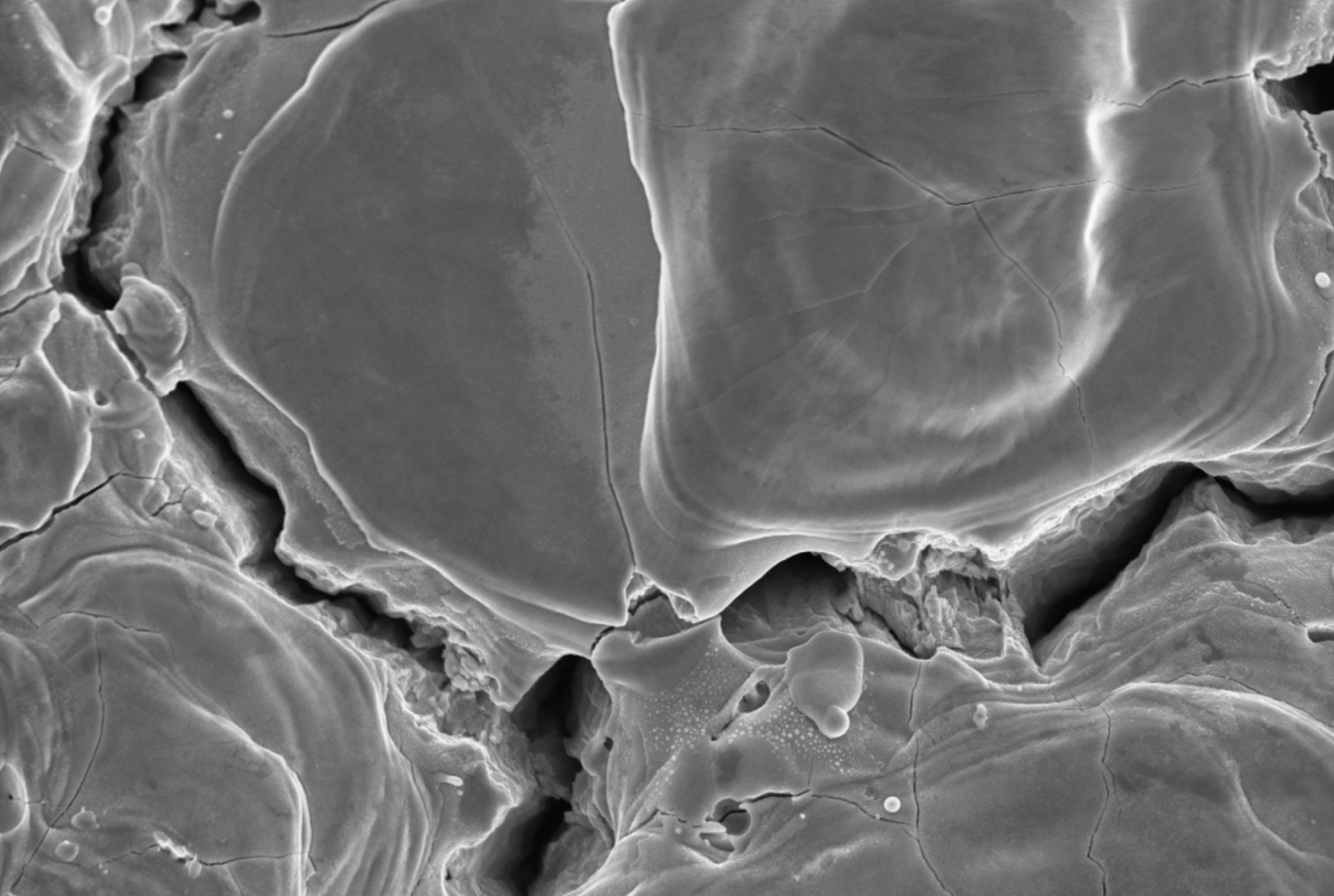


Mag = 500 X
EHT = 20.00 kV
Detector = SE1

100µm

Mo. EDM sector at EIG-1. Iris flat, Tilt=60.

File Name = EIG34.tif
Date :18 Oct 2004
G. Arnau TS/MME

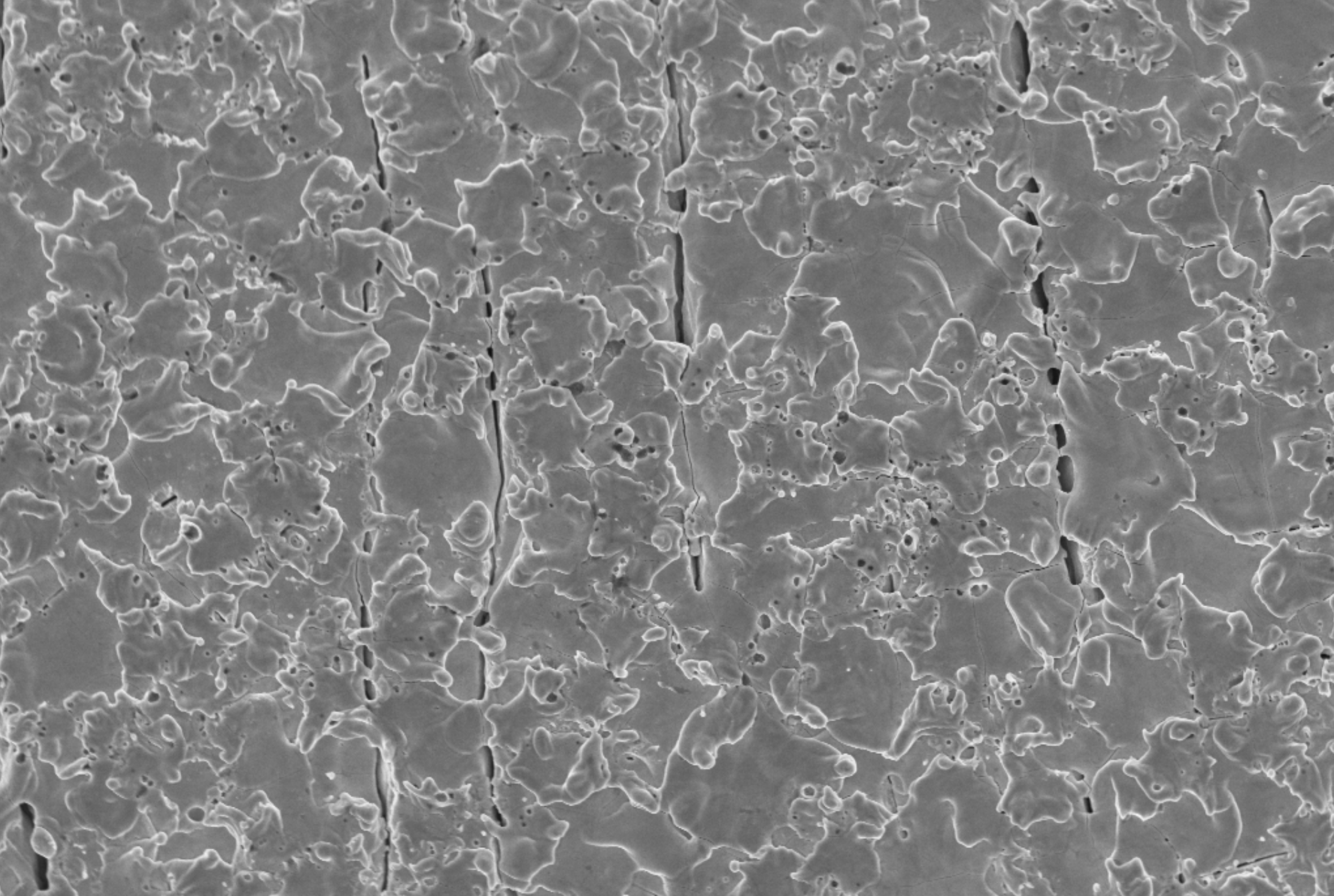


Mag = 1.00 K X
EHT = 20.00 kV
Detector = SE1

10 μ m

Mo. EDM sector at EIG-1. Iris flat side.

File Name = EIG19.tif
Date :17 Oct 2004
G. Arnau TS/MME

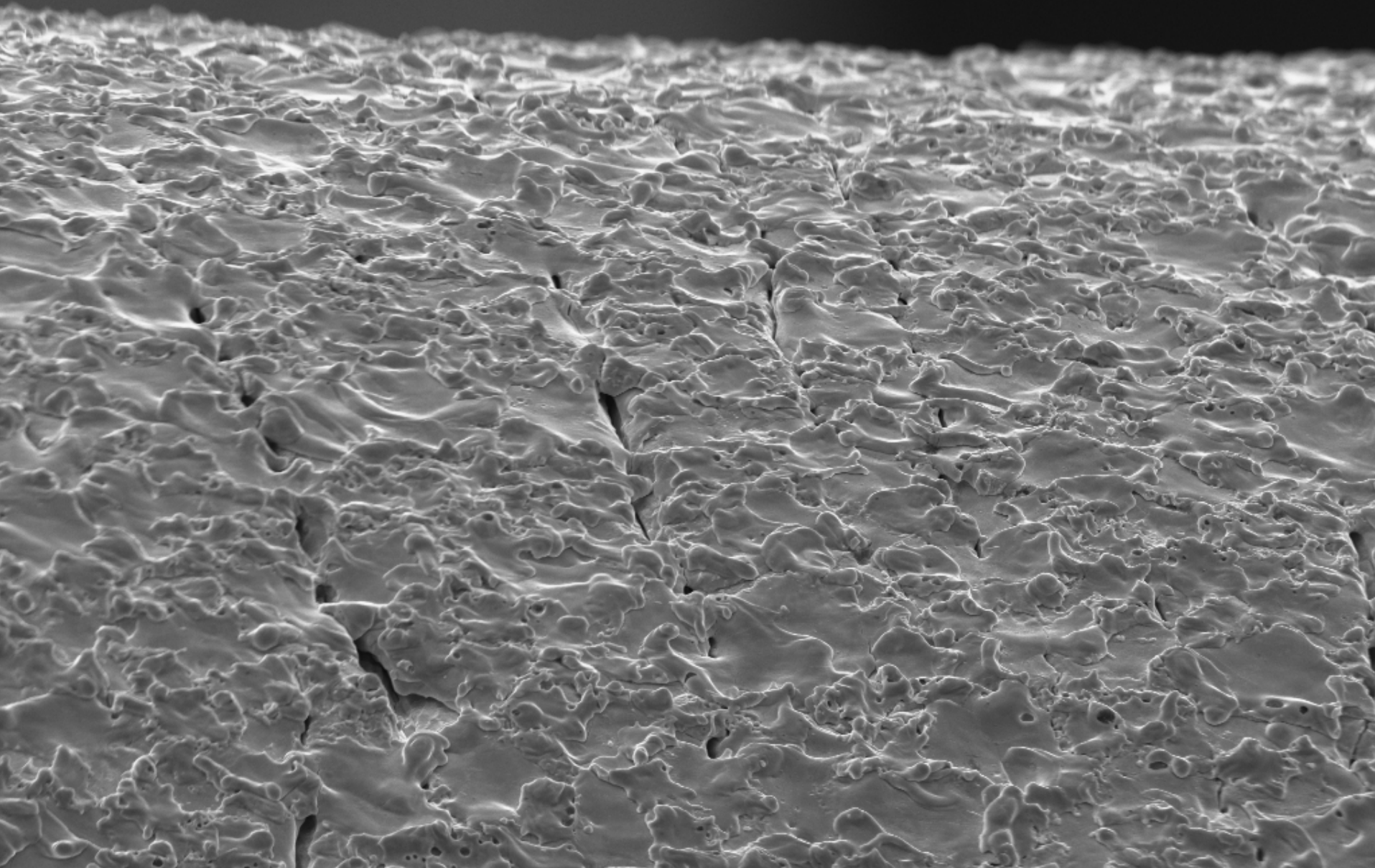


Mag = 500 X
EHT = 20.00 kV
Detector = SE1

100µm

Mo. EDM sector at EIG-1. Tip of iris.

File Name = EIG03.tif
Date :17 Oct 2004
G. Arnau TS/MME

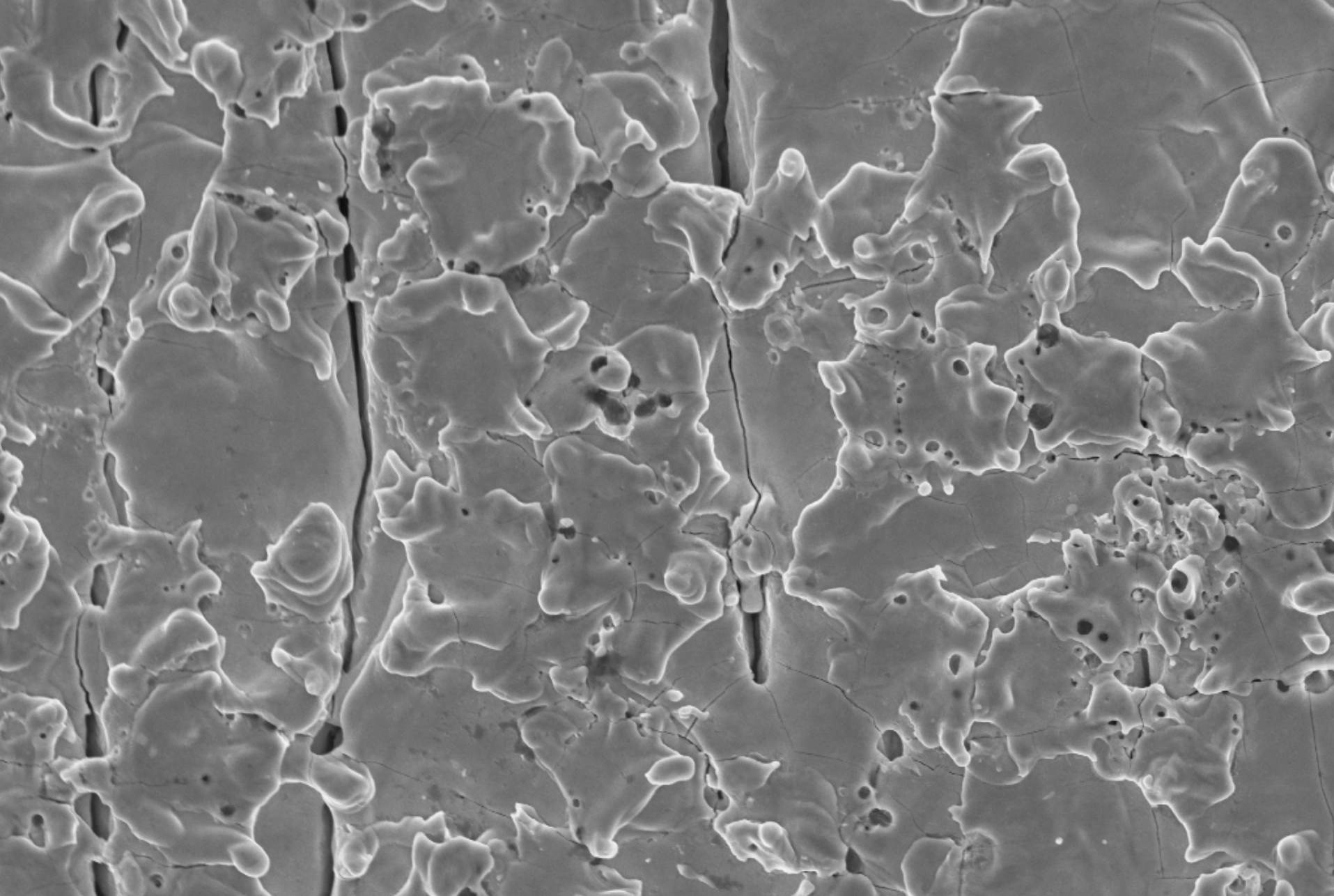


Mag = 500 X
EHT = 20.00 kV
Detector = SE1

100µm

Mo. EDM sector at EIG-1. Iris tip, Tilt=60.

File Name = EIG28.tif
Date :18 Oct 2004
G. Arnau TS/MME

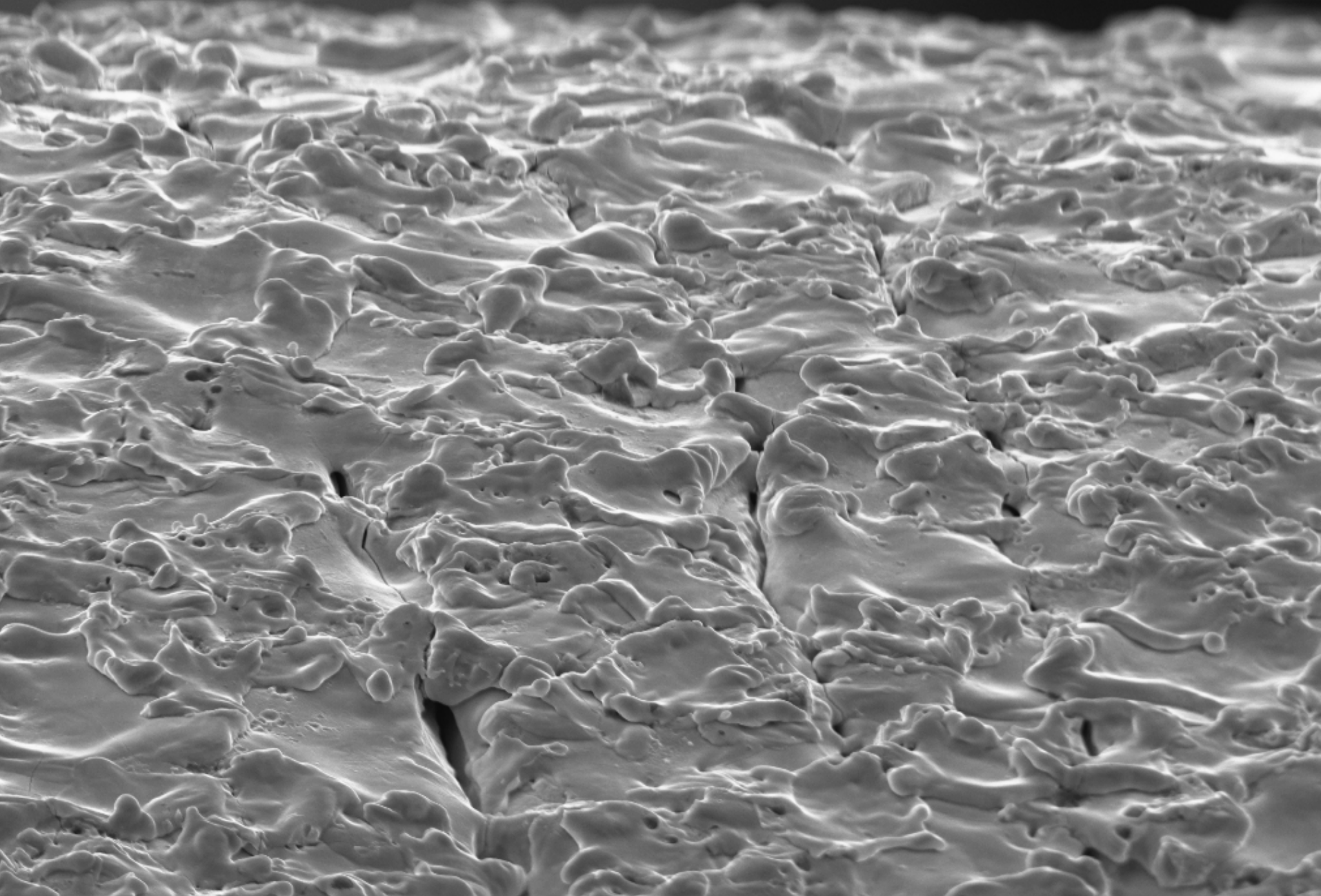


Mag = 1.00 K X
EHT = 20.00 kV
Detector = SE1

10µm
—|—

Mo. EDM sector at EIG-1. Tip of iris.

File Name = EIG06.tif
Date :17 Oct 2004
G. Arnau TS/MME



Mag = 1.00 K X
EHT = 20.00 kV
Detector = SE1

10µm
└──────────┘

Mo. EDM sector at EIG-1. Iris tip, Tilt=60.

File Name = EIG29.tif
Date :18 Oct 2004
G. Arnau TS/MME